## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | DENEROFF ET AL. | Examiner | Paul R. Myers | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0188736	09-2004	Brindle et al.	257/296
	В	US-3,579,229	05-1971	Tripp, Robert W.	341/117
	С	US-3,665,404	05-1972	Werner, John R.	710/262
	D	US-6,073,195	06-2000	Okada, Yukihiro	710/301
	E	US-6,073,188	06-2000	Fleming, Scott M.	710/38
	F	US-5,870,573	02-1999	Johnson, Leith L.	710/316
	G	US-5,481,679	01-1996	Higaki et al.	710/316
	Τ	US-			
	1	US-			
	J	US-			
	ĸ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10092169 A	04-1998	Japan	BRIAN et al.	G11C 05/00
	0	JP 01265345 A	10-1989	Japan	SEKINE, KOICHI	G06F 13/16
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

HOW I MENT DOGINENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	υ	Physical Properties of Gates 3.1-3.60					
	V						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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